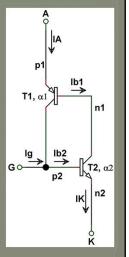


# Regenerative Process

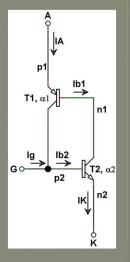
The application of a positive voltage at Anode can not turn on the SCR, because the junction  $J_2$  is reverse biased and Blocking.

Base-Collector junctions of both the transistors are reverse biased and both transistors are off.



# Regenerative Process

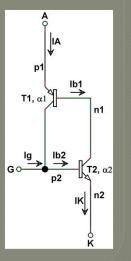
- The collector current of  $\frac{T_2}{T_1}$ .
- The collector current of  $T_1$  along with gate current supplies the base drive for  $T_2$ .



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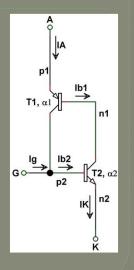
#### The On State

- As the two transistor drive each other into saturation, the excess carrier concentrations in their base regions reach high level injection.
- At this point doping concentrations in the base regions are no longer relevant, and the SCR behaves as a three layer PIN diode.



## The On State

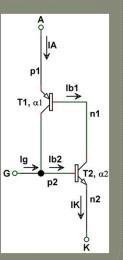
- The two middle layers corresponds to the i-region.
- The forward voltage across the i-region is inversely proportional to the recombination rate.



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# Regenerative Process

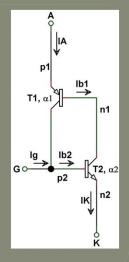
- Base current of each transistor is f times its collector current.
- The regenerative turn on process can be initiated, if a short pulse of current is applied at the gate terminal



# Regenerative Process

As long as the product  $\beta_1, \beta_2 > 1$ 

the two transistors will drive each other harder and harder until they saturate.



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## **Break Over Voltage**

- The SCR does not breakdown in the forward direction, instead it turns on.
- This process is known as Breaking over and the voltage at which it occurs is called the break over voltage  $V_{RO}$ .
- The breaking over process starts due to forward leakage current, I<sub>A</sub> of the SCR which must be kept small to save it from Beak over.

## **Break Over Voltage**

It can be shown that the SCR leakage current is

$$I_A = \frac{I_{CO1} + I_{CO2}}{1 - (\alpha_1 + \alpha_2)}$$
 -----(1)

To keep the I small, the loop gain,

$$(\alpha_1 + \alpha_2) << 1$$

If  $(\alpha_1 + \alpha_2) = 1$ , the equation (1) shows that SCR will enter into sustained breakdown.

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## **Break Over Voltage**

- The leakage current of the SCR increases with temperature.
- Therefore at elevated temperature, the thermally generated leakage current can be sufficient to increase the SCR loop gain such that turn on occur.
- If  $\alpha_2$  is made smaller than  $\alpha_1$ , the reverse and forward breakdown voltages are nearly same.

# SCR dv/dt Rating

- The SCR can also turn on by means of high dv/dt across anode and cathode.
- The increasing voltage is supported by 1/2.
- The associated SCL width increases and a charging current flows across the anode and cathode junctions, causing hole and electron injection respectively.

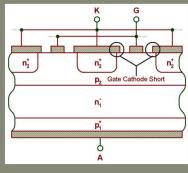
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## SCR dv/dt Rating

The same mechanism occurs at the cathode when gate current is applied; hence if the terminal dv/dt is large enough, SCR turns on.

## **Gate Cathode Short**

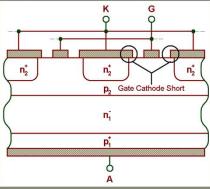
A structural modification is used to reduce temperature sensitivity of the device and to increase the rating by introducing gate cathode shorts.



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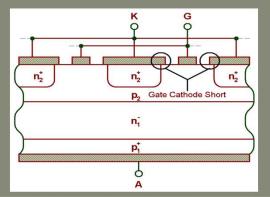
### **Gate Cathode Short**

The effect of this short is like placing a resistor across the base-emitter junction of  $\frac{\Gamma_2}{\kappa}$ .



#### **Gate Cathode Short**

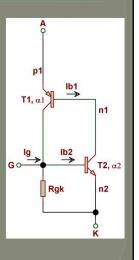
The cathode electron injection efficiency is effectively reduced thereby decreasing  $\alpha_2$  which results in  $V_{RO}$  and dv/dt rating.



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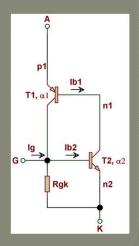
#### **Function of Cathode Short**

- In the forward blocking state, J<sub>2</sub> leakage current will forward bias base-emitter of T<sub>2</sub>
- As this junction voltage rises, the cathode short diverts some of the leakage current of  $p_2$  base reducing the current that is multiplied by the transistor action, in effect the gain of  $T_2$  is reduced.



#### **Function of Cathode Short**

The designer will make 0.7/R<sub>gk</sub> larger than the maximum leakage current expected when SCR is in forward blocking state.



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# Latching Current

- To turn on the SCR, we need  $T_2$  to contribute to the regenerative process.
- This contribution will not occur until the current flowing through the SCR is  $0.7/R_{ak}$ .
- Because this value of current is usually exceeded by  $I_g$ , the SCR will turn on by the gate drive.

## Latching Current

- But if the gate drive is removed, the regenerative process stops and the SCR returns to its off state.
- The Anode current level required for the SCR to remain on when the gate drive is removed is called the latching current  $I_{t}$ .

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## **Holding Current**

Similarly, if the SCR is on and the gate drive has been removed, the anode current must fall below than a critical level to turn off the SCR because of the failure of the regenerative process.

The anode current at which this occurs is called the holding current,  $I_H$ .

Our simple description here suggests that

$$I_{L} = I_{H} = 0.7/R_{col}$$

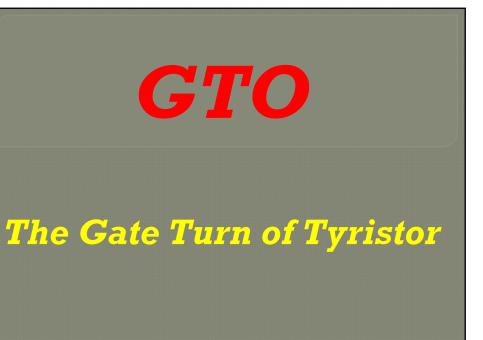
## **Holding Current**

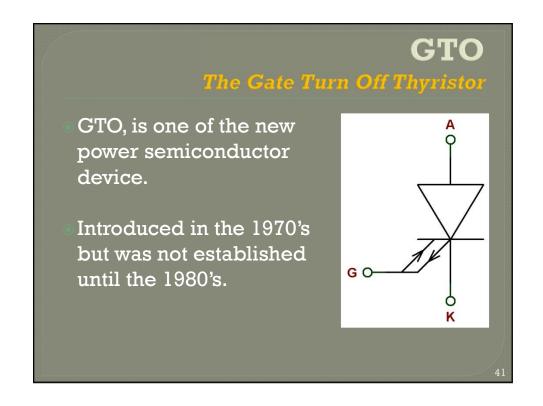
- However,  $R_{gk}$  is slightly different for the turn-on and turn-off processes owing to the differences in excess charge concentrations in the  $p_2$  region.
- For a 100A device,  $I_L$  and  $I_H$  are typically in the range of 100 to 300mA, with  $I_H < I_L$ .

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#### Latched SCR

- An important property of the SCR is that once latched on, the gate control is lost.
- The SCR can not turned off through gate.
- SCR turn off can only be achieved by reducing the anode current externally to a level below which the loop gain is significantly less than unity.





# Research and development has led to the present day range of devices, with peak turn-off current in the range of 300A to 4000A and rated forward blocking voltages of between 1300V and 6000V.

